2657A

High Power System SourceMeter® Instrument





- Source or sink up to 180W of DC or pulsed power (±3000V@20mA, ±1500V@120mA)
- 1fA low current resolution
- Dual 22-bit precision ADCs and dual 18-bit 1µs per point digitizers for high accuracy and high speed transient capture
- Fully TSP[®] compliant for easy system integration with other Series 2600A System SourceMeter models
- **Combines a precision power** supply, current source, DMM, arbitrary waveform generator, V or I pulse generator, electronic 18-bit load, and trigger controller - all in one instrument
- Includes TSP[®] Express characterization software, LabVIEW[®] driver, and Keithley's Test Script Builder software development environment

TYPICAL APPLICATIONS

- Power semiconductor device characterization and testing
- Characterization of GaN, SiC, and other compound materials and devices
- Breakdown and leakage testing to 3kV
- Characterization of sub-millisecond transients

1.888.KEITHLEY (U.S. only) www.keithley.com

The Model 2657A is a high voltage, high power, low current source measurement unit (SMU) instrument that delivers unprecedented power, precision, speed, flexibility, and ease of use to improve productivity in R&D, production test, and reliability environments. The Model 2657A is designed specifically for characterizing and testing high voltage electronics and power semiconductors, such as diodes, FETs, and IGBTs, as well as other components and materials in which high voltage, fast response, and precise measurements of voltage and current are required. The Model 2657A joins Keithley's Series 2600A family of power semiconductor characterization and test solutions to offer the highest power and best low current performance in the industry. These custom-configurable solutions are supported by the industry's most powerful parametric characterization software platforms to grow with you as your applications evolve.

The Model 2657A, like every Series 2600A SourceMeter instrument, offers a highly flexible, fourquadrant voltage and current source/load coupled with precision voltage and current meters. It can be used as a:

Semiconductor characterization instrument

Precision power supply with V and I readback

- V or I waveform generator
- V or I pulse generator

- Digital multimeter (DCV, DCI, ohms, and power with 6¹/₂-digit resolution)
- · Precision electronic load

- True current source
 - +120 mA +60 mA +20 mA 0 mA -20 mA -60 mA -120 mA \mathbb{H} -3 kV -1.5 kV 0 kV +1.5 kV +3 kV

The Model 2657A can source or sink up to 3000V @ 20mA or 1500V @ 120mA.



2657A

Ordering Information

2657A	High Power System SourceMeter Instrumen
8010	High Power Device Test Fixture
Accessories Supplied 7709-308A Digital I/O and	
7709-30	8A Digital I/O and Interlock Connector

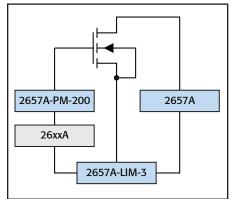
Interlock Connector CA-180-3A TSP-Link/Ethernet Cable Documentation CD Software tools and drivers CD

ACCESSORIES AVAILABLE

2657A-LIM-3	Low Interconnect Module
2657A-PM-200	200V Protection Module
4299-6	Fixed Rack Mount Kit
SHV- CA-553-x	High Voltage Triax to SHV Cable (1, 2, 3m)
HV- CA-554-x	High Voltage Triax to Triax Cable (0.5, 1, 2, 3m)
HV- CA-571-3	High Voltage Triax to Unterminated Cable
HV- CS-1613	High Voltage Triax Feedthrough Connector
ACCESSORIE	S SUPPLIED WITH THE 8010
CA-558-2	25-pin D-sub Interlock Cable for 26xxA
CA-560-x	4mm Black and Red Banana Cables, 8 in.
CA-560-x CA-562-x	4mm Black and Red Banana Cables, 8 in. 6mm Black and Red Banana Cables, 10 in.
0	,
CA-562-x	6mm Black and Red Banana Cables, 10 in.

ACCESSORIES AVAILABLE FOR THE 8010

8010-CTBCustomizable Test Board8010-DTB-220Device Test Board with TO-220 Socket (1.5kV)



The Model 2657A can be combined with other Series 2600A and Model 4200-SCS SMUs to support multi-terminal test capability. The Models 2657A-PM-200 Protection Module and 2657A-LIM-3 Low Interconnect Module make it easier to connect multiple instruments to a probe station safely (not required for connecting to the Model 8010 High Power Device Test Fixture).

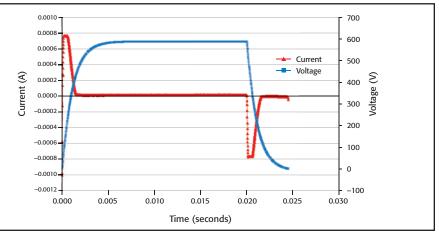
1.888.KEITHLEY (U.S. only) www.keithley.com

High Power System SourceMeter Instrument

Two Measurement Modes: Digitizing or Integrating

Precisely characterize transient and steady-state behavior, including rapidly changing thermal effects, with the two measurement modes in the Model 2657A. Each mode is defined by its independent analog-to-digital (A/D) converters.

The digitizing measurement mode provides speeds up to $1\mu s$ per sample. The dual 18-bit digitizers allow you to capture voltage and current transients simultaneously. In the integrating measurement mode, the dual 22-bit integrating analog to digital converters allow more precise measurement of voltage and current. Two A/D converters are used with each measurement mode, one for current and the other for voltage, that run simultaneously for accurate source readback that does not sacrifice test throughput.



The dual high speed A/D converters will sample as fast as 1µs per point, enabling full simultaneous characterization of both voltage and current.

Expansion Capabilities

Through TSP-Link[®] technology, the Model 2657A can be linked with other Series 2600A instruments to form a larger integrated system with up to 32 nodes. Precision timing and tight channel synchronization are guaranteed with built-in 500ns trigger controllers. The fully isolated, independent channels of the SourceMeter instruments make true SMU-per-pin testing possible.

High Power Device Test Fixture

The Model 8010 High Power Device Test Fixture provides safe and easy connections for testing packaged high power devices at up to 3000V or 100A. The Model 8010 provides connections for a high voltage SourceMeter instrument (Model 2657A), one or two high current SourceMeter instruments (Model 2651A), and three low power SourceMeter instruments (other Series 2600A or Model 4200-SCS SMU instruments). This allows devices with two terminals (diodes) or three terminals (transistors) or even four or five terminals to be characterized safely and accurately. The Model 8010 has full interlock capability for up to six SourceMeter instruments. The Model 8010 has integrated protection circuits that protect the low voltage SourceMeter instruments from high voltages the Model 2657A can output should a device fault occur. The Model 8010 includes both a high current (100A) and a high voltage (3000V) test socket. Various replacement test socket modules are available, including TO-247, TO-220, axial lead, and a blank socket module that allows building a custom socket. In addition to standard banana jumpers, the Model 8010 has rear-panel scope and thermal probe ports to simplify system integration.



Standard Capabilities of Series 2600A Instruments

Each Model 2657A includes all the features and capabilities provided in the other Series 2600A SourceMeter instruments:

- Flexibility for use as either a bench-top I-V characterization tool or as a building block component of multiple channel I-V test systems.
- TSP Express software to perform common I-V tests quickly and easily without programming or installing software.
- ACS Basic Edition software for semiconductor component characterization (optional). ACS Basic Edition now features a "Trace" mode for generating a suite of characteristic curves.
- Keithley's Test Script Processor (TSP) technology supports creating and running custom user test scripts for high speed test automation, as well as creating programming sequences that allow the instrument to operate asynchronously without direct PC control.
- Parallel test execution and precision timing when multiple Series 2600A instruments are connected together in a system.
- LXI Class C compliance.
- 14 digital I/O lines for direct connection to a probe station, component handler, or other automation tools.
- USB port for extra data and test program storage via USB memory device.

High Power System SourceMeter Instrument

Model 2657A Condensed Specifications

VOLTAGE ACCURACY SPECIFICATIONS¹

Source		Measure			
Range	Programming Resolution	Accuracy ±(% rdg + volts)	Display Resolution	Integrating ADC Accuracy ² ±(% rdg + volts)	High Speed ADC Accuracy ³ ±(% rdg + volts)
200 V	5 mV	0.03% + 50 mV	100 µV	0.025% + 50 mV	0.05% + 100 mV
500 V	10 mV	0.03% + 125 mV	$100 \mu V$	0.025% + 100 mV	0.05% + 200 mV
1500 V	40 mV	0.03% + 375 mV	1 mV	0.025% + 300 mV	0.05% + 600 mV
3000 V	80 mV	0.03% + 750 mV	1 mV	0.025% + 600 mV	0.05% + 1.2 V

CURRENT ACCURACY SPECIFICATIONS 4

Source		Measure			
Range	Programming Resolution	Accuracy ±(% rdg + amps)	Display Resolution	Integrating ADC Accuracy ² ±(% rdg + amps)	High Speed ADC Accuracy ³ ±(% rdg + amps)
1 nA	30 fA	$0.1\% + 2E^{-12} + VoE^{-15}$	1 fA	$0.1\% + 6E^{-13} + VoE^{-15}$	$0.2\% + 6E^{-13} + VoE^{-15}$
10 nA	300 fA	$0.1\% + 5E^{-12} + VoE^{-15}$	10 fA	$0.1\% + 5E^{-12} + VoE^{-15}$	$0.2\% + 5E^{-12} + VoE^{-15}$
100 nA	3 pA	$0.1\% + 6E^{-11} + VoE^{-13}$	100 fA	$0.1\% + 6E^{-11} + VoE^{-13}$	$0.2\% + 6E^{-11} + VoE^{-13}$
1 μA	30 pA	0.03% + 700 pA	1 pA	0.025% + 400 pA	0.08% + 800 nA
$10 \ \mu A$	300 pA	0.03% + 5 nA	10 pA	0.025% + 1.5 nA	0.08% + 3 nA
100 µA	3 nA	0.03% + 60 nA	100 pA	0.02 % + 25 nA	0.05% + 50 nA
1 mA	30 nA	0.03% + 300 nA	1 nA	0.02 % + 200 nA	0.05% + 400 nA
2 mA	60 nA	$0.03\% + 1.2 \mu\text{A}$	1 nA	0.02 % + 500 nA	$0.05\% + 1 \mu A$
20 mA	600 nA	$0.03\% + 12 \mu\text{A}$	10 nA	$0.02 \% + 5 \mu A$	$0.05\% + 10 \mu\text{A}$
120 mA	3 µA	0.03% + 36 μA	100 nA	$0.02 \% + 24 \mu A$	$0.05\% + 50 \mu\text{A}$

1. For temperatures 0° to 18°C and 28° to 50°C, accuracy is degraded by $\pm (0.15 \times \text{accuracy specification})/^{\circ}C$.

 Derate accuracy specification for NPLC setting <1 by increasing error term. Add appropriate typical percent of range term for resistive loads using the table below.

NPLC Setting	200 V and 500V Ranges	1500V and 3000 V Ranges	100 nA Range	1 μA to 120 mA Ranges
0.1	0.01%	0.01%	0.01%	0.01%
0.01	0.08%	0.07%	0.1 %	0.05%
0.001	0.8 %	0.6 %	1 %	0.5 %

3. 18-bit ADC. Average of 1000 samples taken at 1µs intervals.

4. For temperatures 0° to 18°C and 28° to 50°C, accuracy is degraded by $\pm (0.35 \times accuracy \text{ specification})/°C$.

SUPPLEMENTAL CHARACTERISTICS

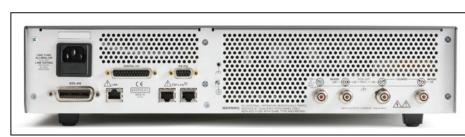
TYPICAL VOLTAGE SOURCE NOISE: 0.005% of range. TYPICAL CURRENT SOURCE NOISE: 0.08% of range. TYPICAL VOLTAGE SOURCE SETTLING: <1ms to 200V, <7ms to 3000V. TYPICAL CURRENT SOURCE SETTLING: <5ms to 120mA, <200ms to 1μA.

Specifications are subject to change without notice.



Model 8010 High Power Device Test Fixture.

1.888.KEITHLEY (U.S. only) www.keithley.com



Model 2657A rear panel.



SMU INSTRUMENTS

2657A

High Power System SourceMeter Instrument

TRIGGERING AND SYNCHRONIZATION SPECIFICATIONS

TRIGGERING: Trigger In to Trigger Out: 0.5µs, typical.

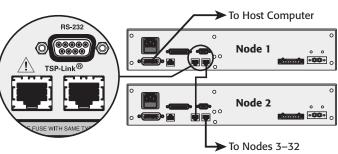
 $\label{eq:synchronized} \textbf{SYNCHRONIZATION: Single- or multi-node synchronized source change: <0.5 \mu s, typical.}$

PROGRAMMING

- TEST SCRIPT BUILDER: Integrated development environment for building, running, and managing TSP scripts.
- TSP EXPRESS (Embedded): Tool that allows users to perform common I-V tests quickly and easily without programming or installing software.
- SOFTWARE INTERFACE: TSP Express (Embedded), Direct GPIB/VISA, Read/Write with VB, VC/C++, VC#, LabVIEW, TestPoint, LabWindows/CVI, etc.

SYSTEM EXPANSION

The TSP-Link expansion interface allows TSP-enabled instruments to trigger and communicate with each other. See figure below:



USB: USB 2.1 Host Controller, supports external data storage.
CONTACT CHECK: $\pm 50\Omega$
PC INTERFACE: IEEE-488.1 and .2; LXI Class C Ethernet; RS-232.
DIGITAL I/O INTERFACE: Input/Output Pins: 14 open drain I/O bits. 5.25V max.
POWER SUPPLY: 100V to 250VAC, 50Hz-60Hz (auto sensing), 550VA max
COOLING: Forced air. Side and top intake and rear exhaust.
EMC: Conforms to European Union EMC Directive.
SAFETY: ETL listed (PENDING). Conforms to European Union Low Voltage Directive.
WARRANTY: 1 year.
DIMENSIONS: 89mm high × 435mm wide × 549mm deep (3.5 in × 17.1 in × 21.6 in). Benc Configuration (with handle and feet): 104mm high × 483mm wide × 620mm deep (4.1 in × 19 in × 24.4 in).
WEIGHT: 9.98kg (22 lbs).
ENVIRONMENT: For indoor use only.
CALIBRATION PERIOD: One year.



Specifications are subject to change without notice. All Keithley trademarks and trade names are the property of Keithley Instruments, Inc. All other trademarks and trade names are the property of their respective companies.



A GREATER MEASURE OF CONFIDENCE

KEITHLEY INSTRUMENTS, INC. 🛛 28775 AURORA RD. 🗖 CLEVELAND, OH 44139-1891 🗖 440-248-0400 🗖 Fax: 440-248-6168 🗖 1-888-KEITHLEY 層 www.keithley.com

BELGIUM

Sint-Pieters-Leeuw Ph: 02-3630040 Fax: 02-3630064 info@keithley.nl www.keithley.nl

ITALY

SMU INSTRUMENTS

Peschiera Borromeo (Mi) Ph: 02-5538421 Fax: 02-55384228 info@keithley.it www.keithley.it

SINGAPORE

Singapore Ph: 65-6747-9077 Fax: 65-6747-2991 sea@keithley.com www.keithley.com.sg

CHINA

Beijing Ph: 86-10-8447-5556 Fax: 86-10-8225-5018 china@keithley.com www.keithley.com.cn

JAPAN

Tokyo Ph: 81-3-6714-3070 Fax: 81-3-6714-3080 info.jp@keithley.com www.keithley.jp

SWITZERLAND

Brugg Ph: 41-56-460-7890 Fax: 41-56-460-7879 info@keithley.ch www.keithley.ch

FRANCE

Les Ulis Ph: 01-69868360 Fax: 01-69868361 info@keithley.fr www.keithley.fr

KOREA

Seoul Ph: 82-2-574-7778 Fax: 82-2-574-7838 keithley@keithley.co.kr www.keithley.co.kr

TAIWAN

Hsinchu Ph: 886-3-572-9077 Fax: 886-3-572-9031 info_tw@keithley.com www.keithley.com.tw

GERMANY

Germering Ph: 089-84930740 Fax: 089-84930734 info@keithley.de www.keithley.de

MALAYSIA

Penang Ph: 60-4-643-9679 Fax: 60-4-643-3794 sea@keithley.com www.keithley.com

UNITED KINGDOM

Bracknell Ph: 044-1344-392450 Fax: 044-1344-392457 info@keithley.co.uk www.keithley.co.uk

INDIA

Bangalore Ph: 080-30792600 Fax: 080-30792688 support_india@keithley.com www.keithley.in

NETHERLANDS

Son Ph: 040-2675502 Fax: 040-2675509 info@keithley.nl www.keithley.nl

